

Attorney's Docket No.: 07977-152003 / US3353D1D1

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hisashi Ohtani  
Serial No. : 10/657,137  
Filed : September 9, 2003  
Title : SEMICONDUCTOR INTEGRATED CIRCUIT AND FABRICATION METHOD THEREOF

Art Unit : 2822  
Examiner : Ida M. Soward

**MAIL STOP RCE**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

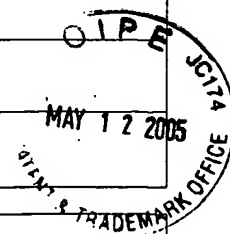
Respectfully submitted,

Date: May 12, 2005

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hisashi Ohtani	
		Filing Date September 9, 2003	Group Art Unit 2822



### U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2002-0179969	12/05/2002	MIYAZAKI et al.			07/12/2002
	AB	2003-0094656	05/22/2003	KOYAMA et al.			11/18/2002
	AC	2003-0173570	09/18/2003	YAMAZAKI et al.			03/18/2003
	AD	2004-0023445	02/05/2004	MIYAZAKI et al.			07/17/2003
	AE	2004-0051102	03/18/2004	MIYAZAKI et al.			08/15/2003
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature	Date Considered
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EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.